

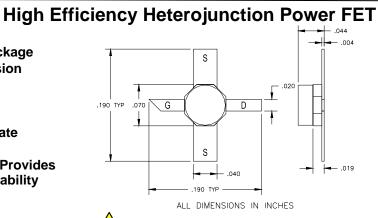
# EPA018B-70

## ISSUED 11/01/2007

## FEATURES

- Non-Hermetic Low Cost Ceramic 70mil Package
- +20.0 dBm Output Power at 1dB Compression
- 11.0 dB Power Gain at 18GHz
- Typical 0.75 dB Noise Figure and 12.5 dB Associated Gain at 12GHz
- 0.3 x 180 Micron Recessed "Mushroom" Gate
- Si<sub>3</sub>N<sub>4</sub> Passivation
- Advanced Epitaxial Heterojunction Profile Provides Extra High Power Efficiency, and High Reliability

ELECTRICAL CHARACTERISTICS (T<sub>a</sub> = 25°C)



## Caution! ESD sensitive device.

SYMBOL	PARAMETERS/TEST CONDITIONS			TYP	MAX	UNITS
P <sub>1dB</sub>	Output Power at 1dB Compression	f = 12GHz	18.5	20.0		dBm
		f = 18GHz	44.0	20.0		
G <sub>1dB</sub>	Gain at 1dB Compression	f = 12GHz	11.0	13.5		dB
	V <sub>DS</sub> = 6V, I <sub>DS</sub> ≈ 50% I <sub>DSS</sub>	f =18GHz		11.0		
PAE	Power Added Efficiency at 1dB Compression $V_{DS} = 6V$ , $I_{DS} \approx 50\% I_{DSS}$	f = 12GHz		45		%
NF		f = 12GHz		0.75		dB
GA	Associate Gain $V_{DS}$ = 2V, $I_{DS}$ = 15mA	f = 12GHz		12.5		dB
I <sub>DSS</sub>	Saturated Drain Current V <sub>DS</sub> = 3 V, V	/ <sub>GS</sub> = 0 V	30	55	80	mA
G <sub>M</sub>	Transconductance V <sub>DS</sub> = 3 V, V	/ <sub>GS</sub> = 0 V	35	60		mS
V <sub>P</sub>	Pinch-off Voltage $V_{DS}$ = 3 V, $I_{DS}$	= 1.0 mA		-1.0	-2.5	V
$BV_{GD}$	Drain Breakdown Voltage I <sub>GD</sub> = 1.0mA		-9	-15		V
BV <sub>GS</sub>	Source Breakdown Voltage I <sub>GS</sub> = 1.0mA		-6	-14		V
R <sub>TH</sub>	Thermal Resistance			480*		°C/W

Notes: \* Overall Rth depends on case mounting.

## MAXIMUM RATINGS AT 25°C<sup>1,2</sup>

SYMBOL	CHARACTERISTIC		<b>CONTINUOUS</b> <sup>2</sup>	
V <sub>DS</sub>	Drain to Source Voltage	12 V	6 V	
V <sub>GS</sub>	Gate to Source Voltage	-6 V	-3 V	
I <sub>DS</sub>	Drain Current	ldss	40 mA	
I <sub>GSF</sub>	Forward Gate Current	9 mA	1.5 mA	
P <sub>IN</sub>	Input Power	16 dBm	@ 3dB compression	
PT	Total Power Dissipation	285 mW	240 mW	
Т <sub>сн</sub>	Channel Temperature	175°C	150°C	
T <sub>STG</sub>	Storage Temperature	-65/+175°C	-65/+150°C	

1. Exceeding any of the above ratings may result in permanent damage.

2. Exceeding any of the above ratings may reduce MTTF below design goals.



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ISSUED 11/01/2007

# **High Efficiency Heterojunction Power FET**

## S-PARAMETERS

6V, ½ Idss

FREQ	S	11	S	21	S	S12		S22	
(GHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG	
1.0	0.984	-19.0	5.081	162.1	0.014	75.9	0.813	-11.1	
2.0	0.950	-38.2	4.859	144.2	0.026	63.4	0.789	-23.7	
3.0	0.906	-56.4	4.547	127.3	0.035	51.4	0.766	-35.3	
4.0	0.863	-74.0	4.348	111.9	0.041	42.1	0.745	-44.6	
5.0	0.813	-90.7	4.195	97.2	0.047	32.9	0.713	-53.3	
6.0	0.764	-105.0	3.973	82.9	0.049	24.2	0.675	-64.4	
7.0	0.715	-120.3	3.746	68.8	0.050	15.3	0.649	-74.6	
8.0	0.663	-134.7	3.572	55.9	0.046	6.9	0.612	-82.6	
9.0	0.614	-157.7	3.501	41.4	0.044	5.6	0.605	-87.5	
10.0	0.587	-179.9	3.388	26.4	0.044	2.1	0.585	-97.0	
11.0	0.561	168.8	3.307	13.4	0.044	0.2	0.562	-110.8	
12.0	0.539	153.6	3.248	0.0	0.045	2.0	0.551	-122.8	
13.0	0.573	127.2	3.097	-15.8	0.049	-0.6	0.527	-131.9	
14.0	0.611	104.9	2.873	-31.1	0.050	-6.1	0.510	-143.2	
15.0	0.613	90.9	2.805	-46.4	0.055	-13.0	0.513	-162.9	
16.0	0.620	74.4	2.730	-62.7	0.059	-20.7	0.503	178.0	
17.0	0.640	58.9	2.432	-76.4	0.056	-20.7	0.463	169.1	
18.0	0.692	49.7	2.365	-87.1	0.075	-32.3	0.522	157.0	
19.0	0.691	32.0	2.236	-104.4	0.064	-49.1	0.540	133.7	
20.0	0.731	16.7	2.163	-120.6	0.064	-59.8	0.591	117.3	
21.0	0.783	7.8	2.061	-134.9	0.065	-70.3	0.578	106.6	
22.0	0.771	-2.6	1.923	-148.7	0.062	-85.6	0.592	95.6	
23.0	0.752	-20.8	1.800	-166.5	0.058	-103.2	0.592	76.9	
24.0	0.776	-37.7	1.693	174.8	0.054	-123.0	0.584	59.7	
25.0	0.756	-48.6	1.690	160.0	0.055	-139.5	0.568	45.9	
26.0	0.742	-62.4	1.710	144.5	0.060	-154.9	0.555	33.7	

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